

Measurement of Characteristics of the Pixel Chip for **ALICE-ITS** Upgrade Project

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For the **ALICE-ITS** collaboration

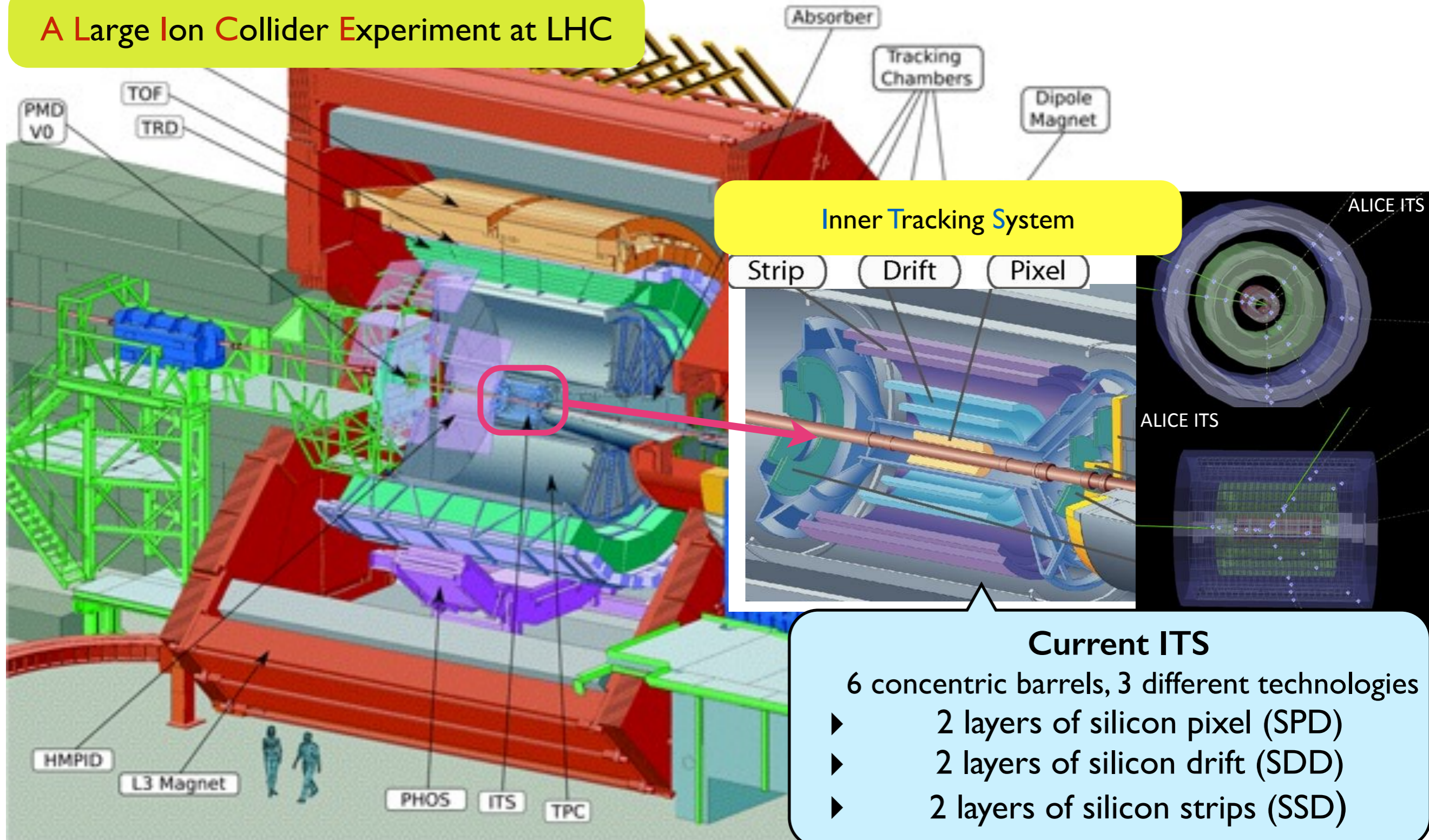
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Introduction

ALICE-ITS

A Large Ion Collider Experiment at LHC



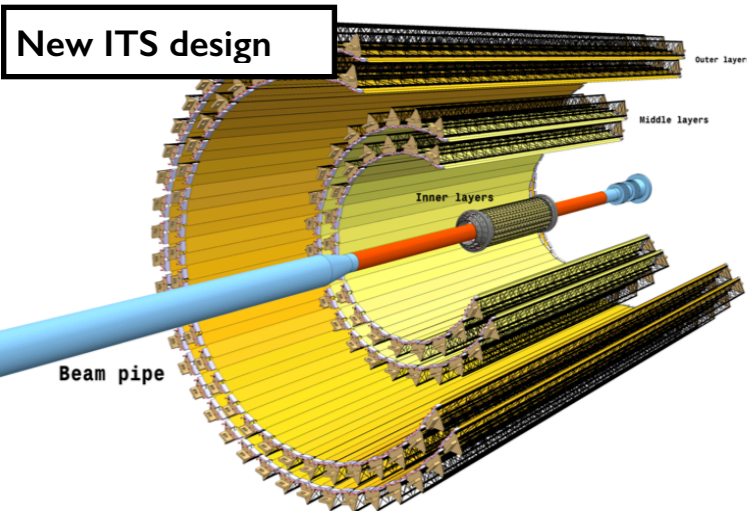
Inner Tracking System

Strip Drift Pixel

Current ITS

- 6 concentric barrels, 3 different technologies
- ▶ 2 layers of silicon pixel (SPD)
- ▶ 2 layers of silicon drift (SDD)
- ▶ 2 layers of silicon strips (SSD)

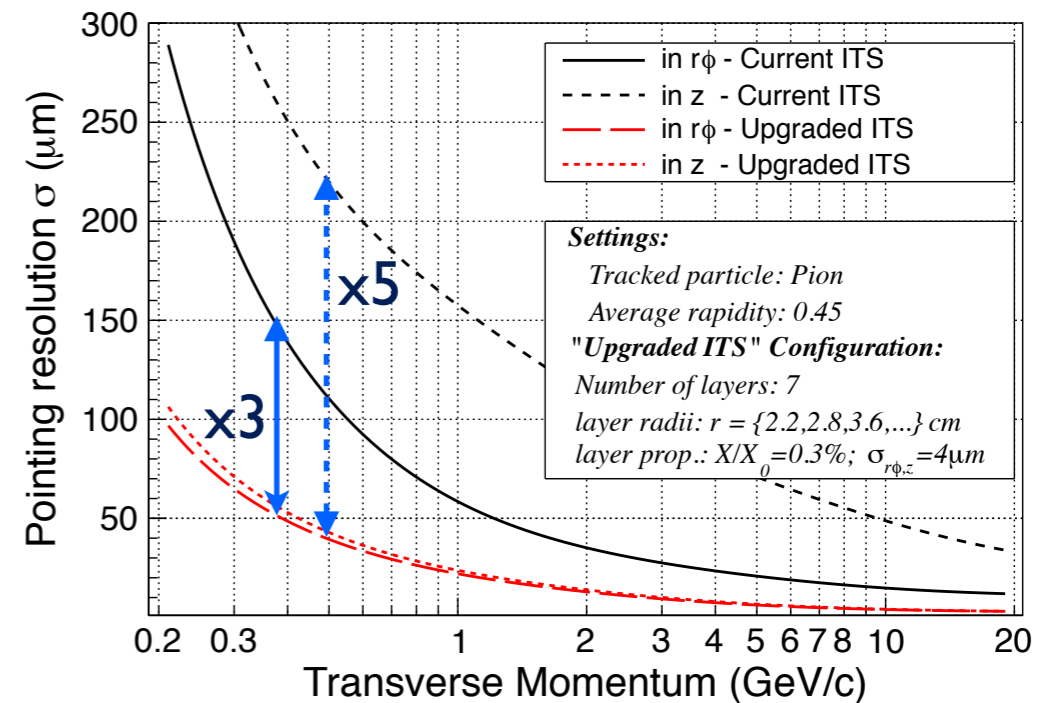
ITS upgrade project



The Goal of ITS upgrade

- High spatial resolution
- Low-material budget
- Fast data acquisition

	Current	New ITS
# of layer	6 layer	7 layer
Pixel size	50 x 425 μm^2	20x20 μm^2 , 50x50 μm^2
Position of 1st layer	39mm	22mm
Material budget per layer	$\sim 1.14\% X_0$	0.3% X_0
Data readout rate	500Hz, 1kHz	> 50kHz, > 1MHz



ITS upgrade project organization

- WP1: Physics
- WP2: Simulation and reconstruction
- WP3: Pixel chip design
- WP4: Sensor post-processing and Mass test pixel

- WP5: Pixel chip characterization test

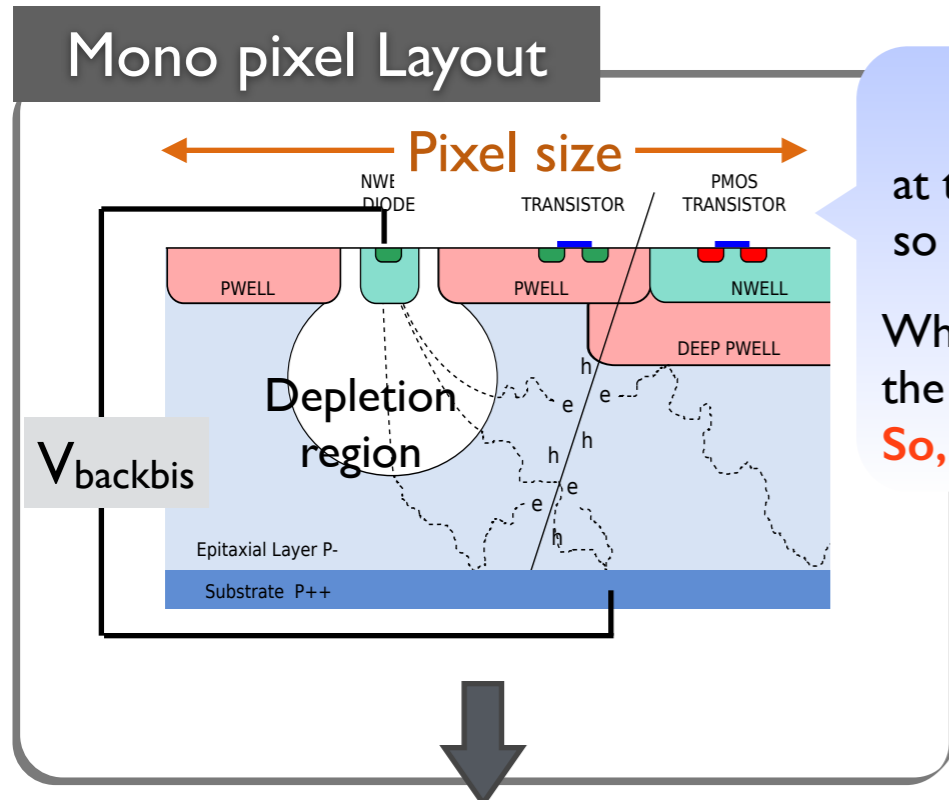
- WP6: Inner Layer Module
- WP7: Middle Layer Module
- WP8: Outer Layer Module
- WP9: Mechanics and cooling
- WP10: Readout Electronics

Main tasks of PNU

- Measurements of characteristics for the ITS prototype pixel chip
- Building up the test system in Korea
- Physics performance (with Inha Univ.)

Measurement of Characteristics of the **ITS** pixel chips

ITS test-system

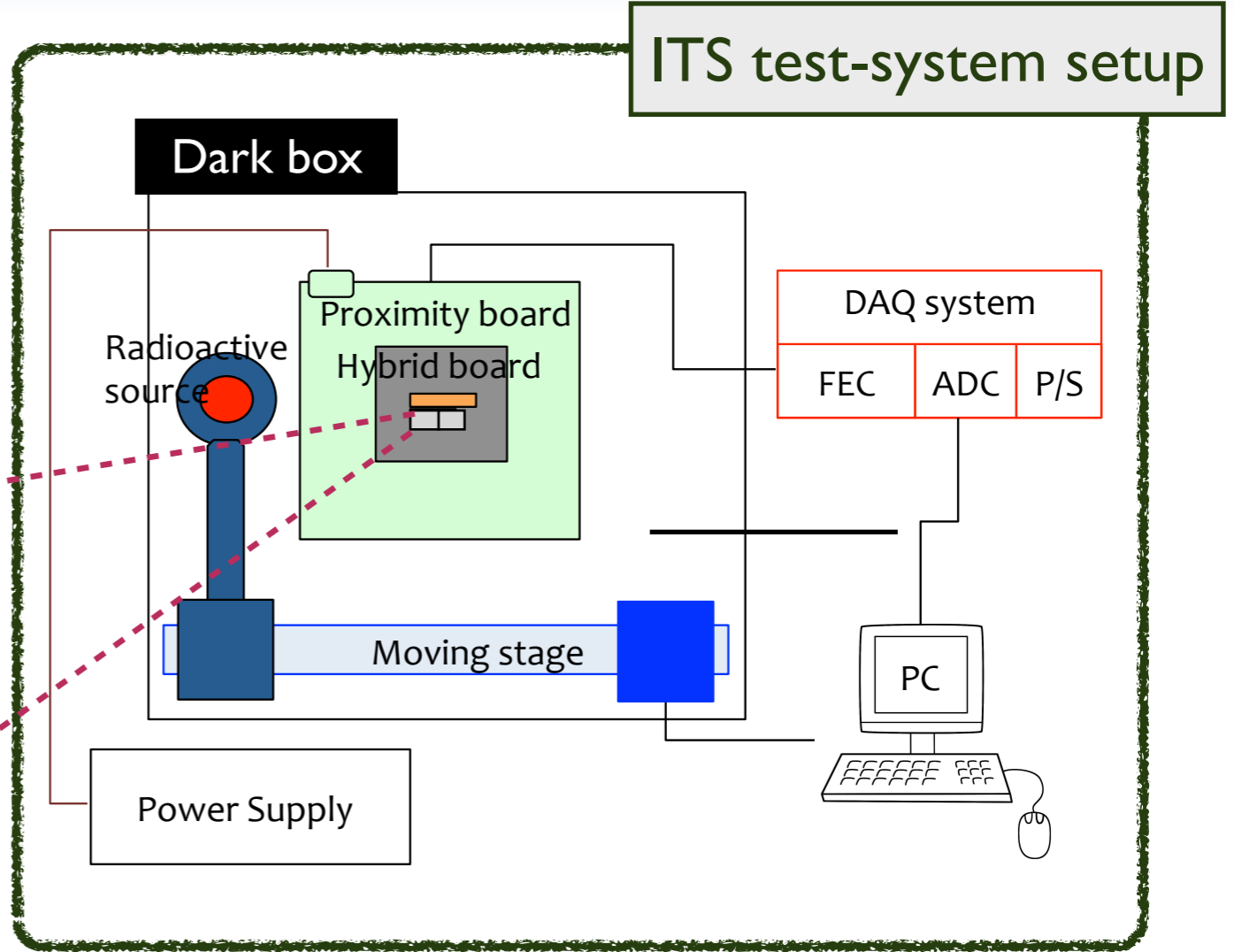
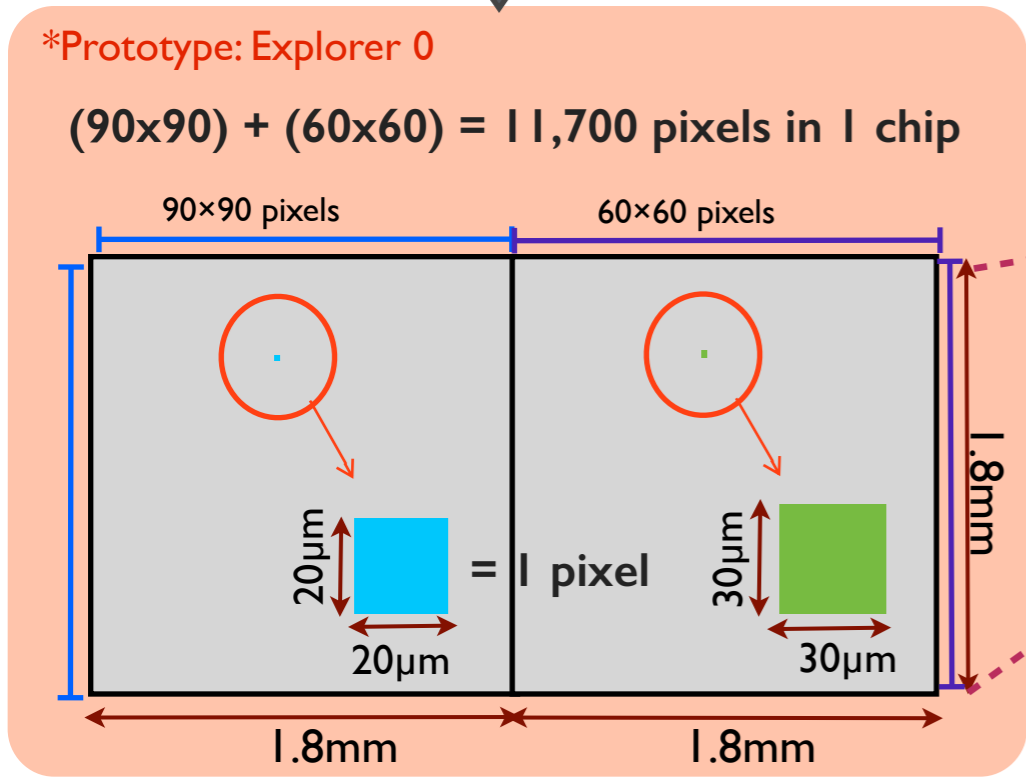


Simple principle

at the p-n junction, a fixed space charge of ionized donors and accepters is created, so called depletion region.

When a Ionizing particle is passing through in the detector, the particle creates electrons. the electrons near a depletion region are collected in n-well diode.

So, the particle position is detected in that way.



Pedestal measurement

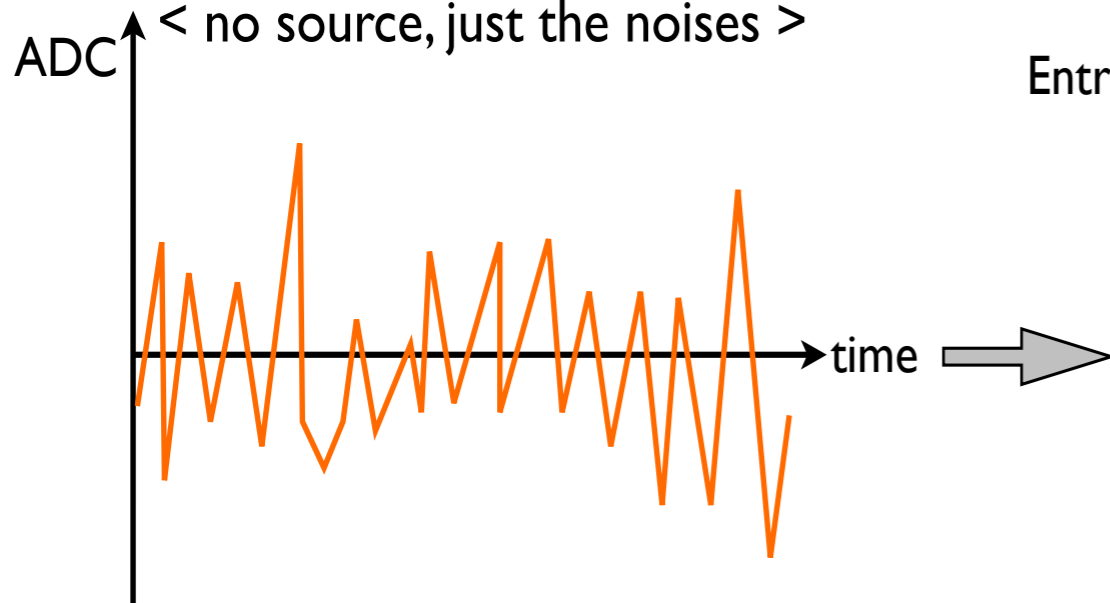
Characterize the pixel chips

Non-irradiated vs. Irradiated*

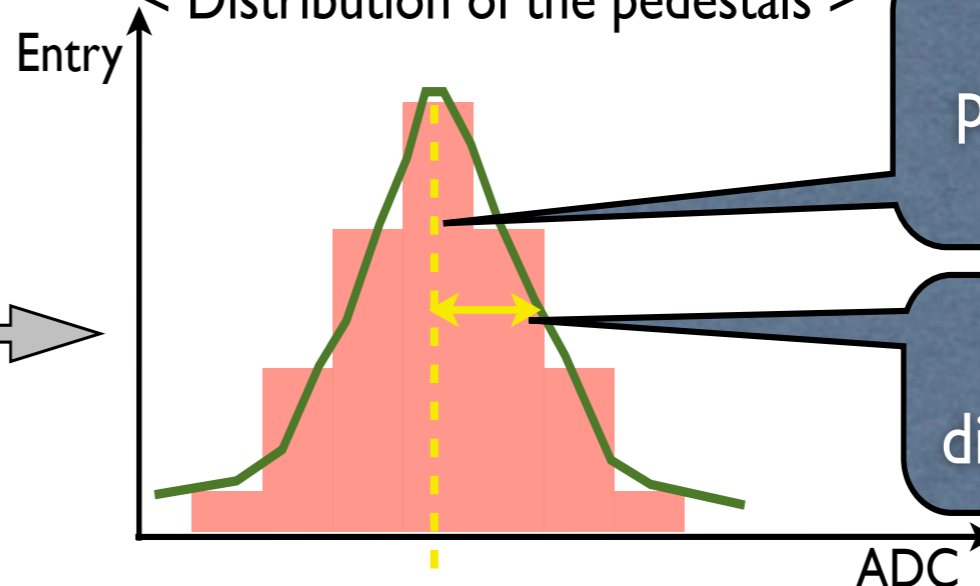
- ✓ Noise behavior
- ✓ Charge collection efficiency
- ✓ Position resolution
- ✓ Detection efficiency

* Radiation level : 1×10^{13} [1MeV n_{eq}/cm^2]
 - including a safety factor of 10 in the whole detector lifetime (for a collected data set corresponding to 10 nb⁻¹ Pb-Pb and 6pb⁻¹ pp collisions)

< no source, just the noises >



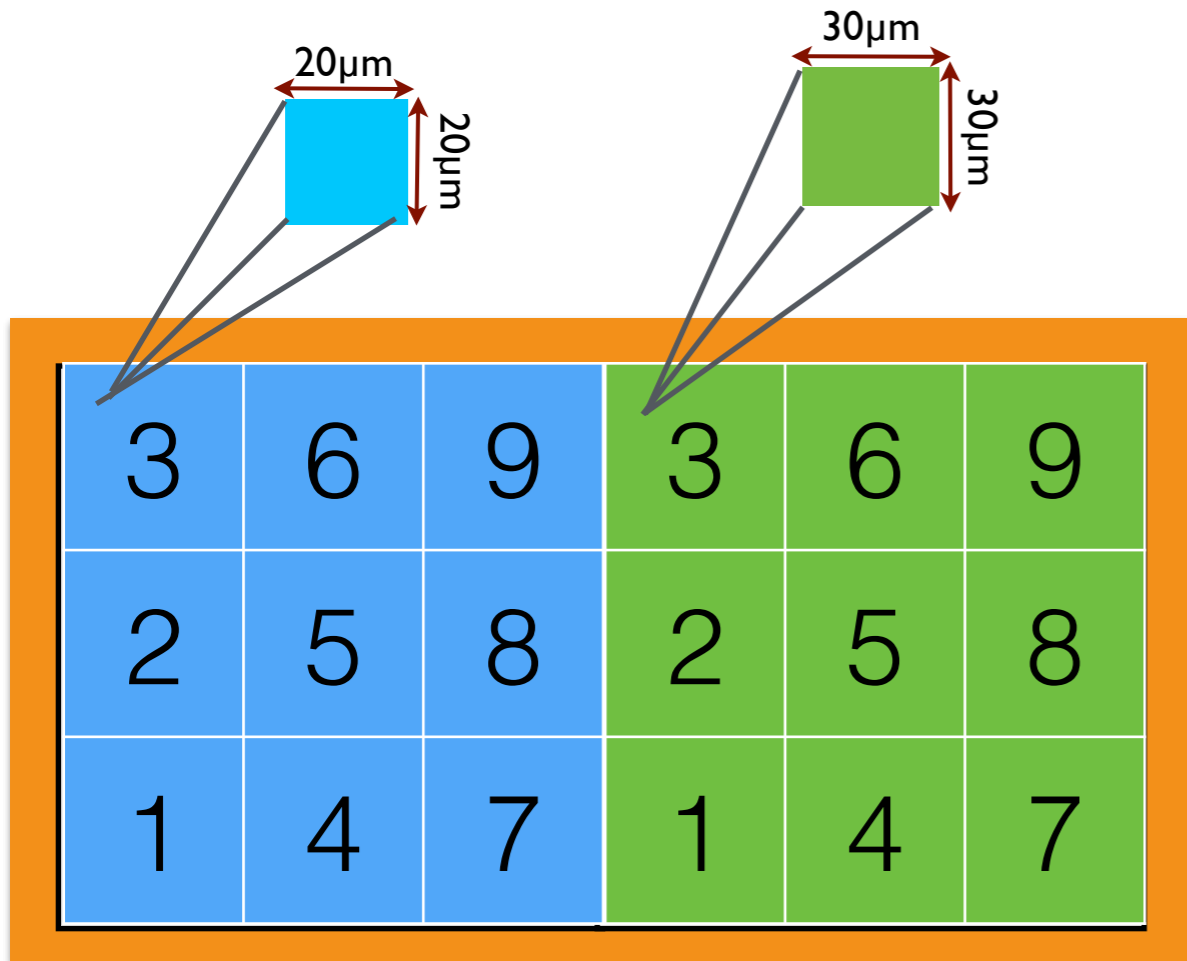
< Distribution of the pedestals >










Mean value of the pedestal distribution = pedestal, M_p

RMS of the pedestal distribution = noise, σ_p

Anode type

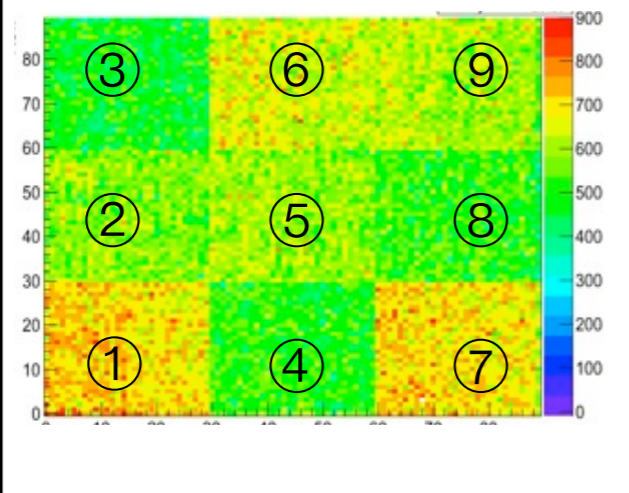
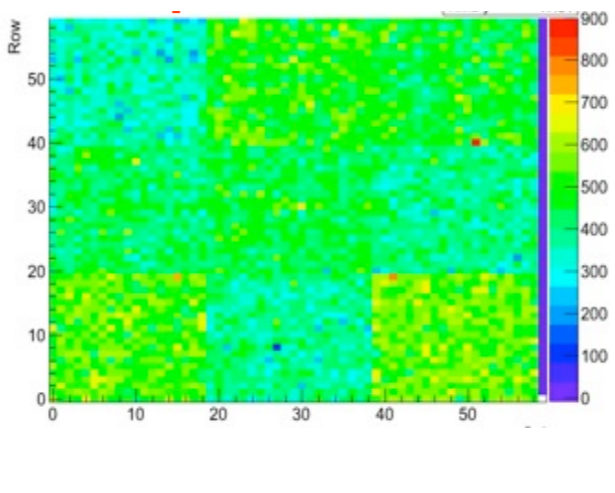
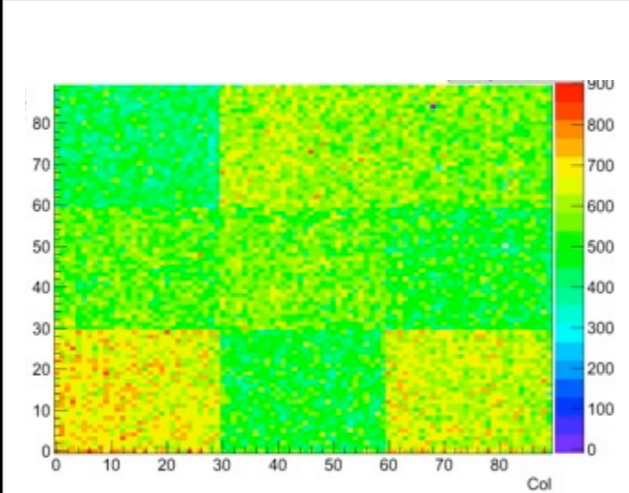
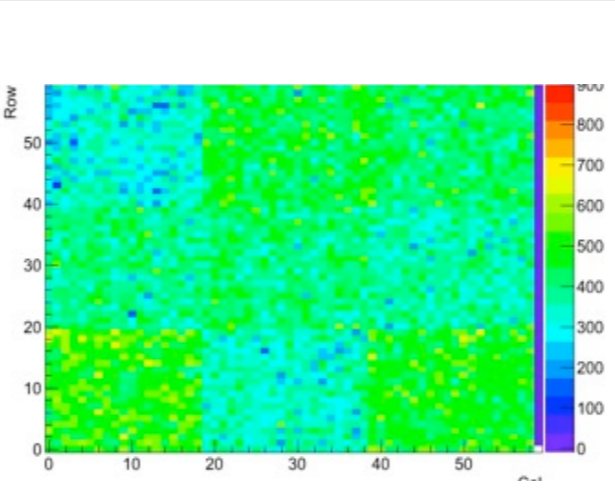


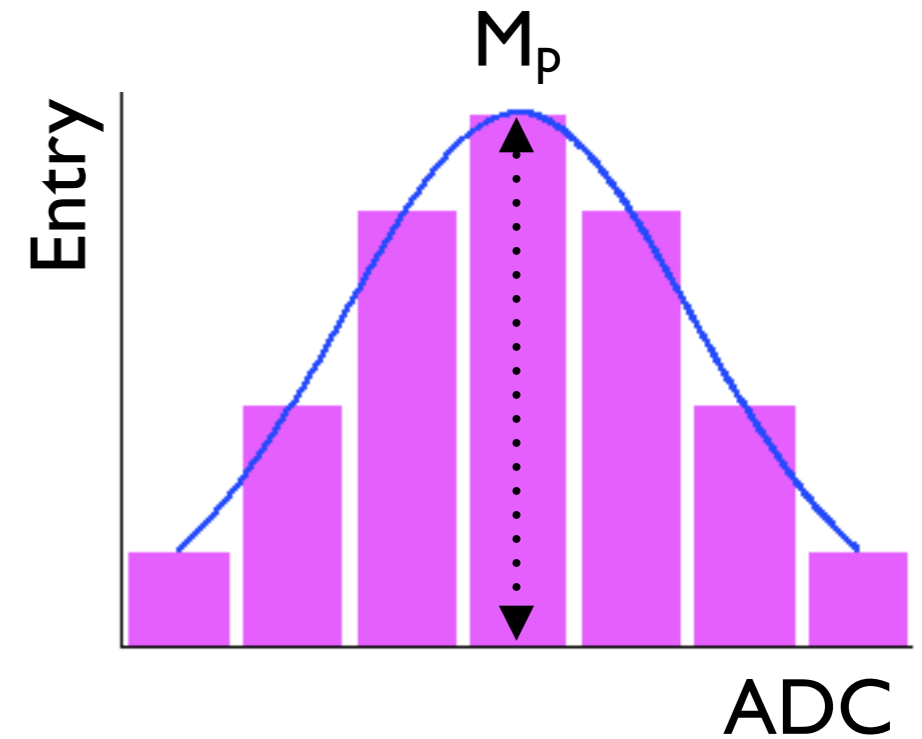
in one chip

Shape	Anode diameter [μm]	Spacing [μm]	Sectors
	2	0	1
	3	0	2, 8
	4	0	3
	3	0	4
	3	0.6	5
	3	1.04	6, 9
	2	1.54	7

Pedestal distribution

Measurement #10. in room temperature not stabilized

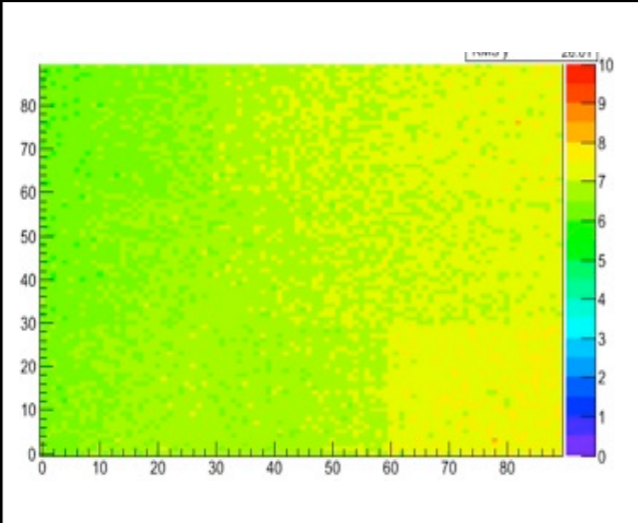
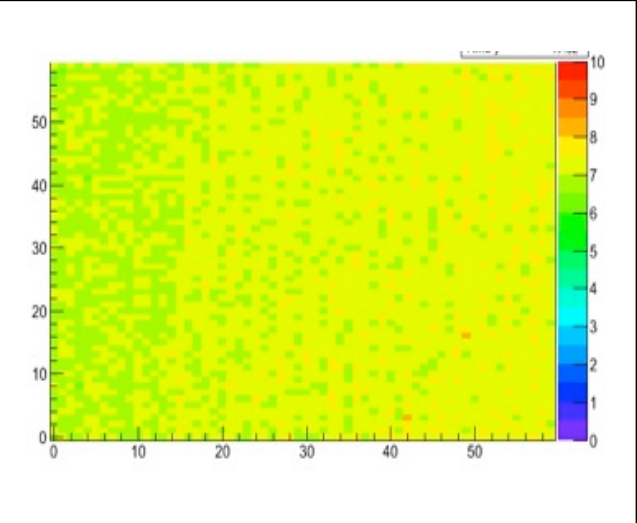
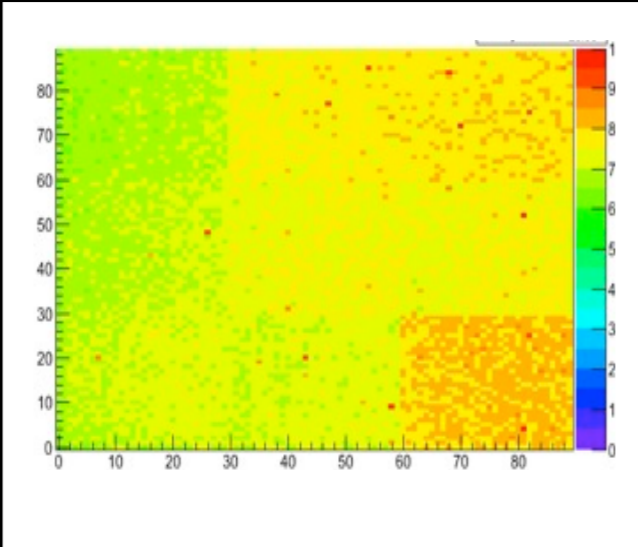
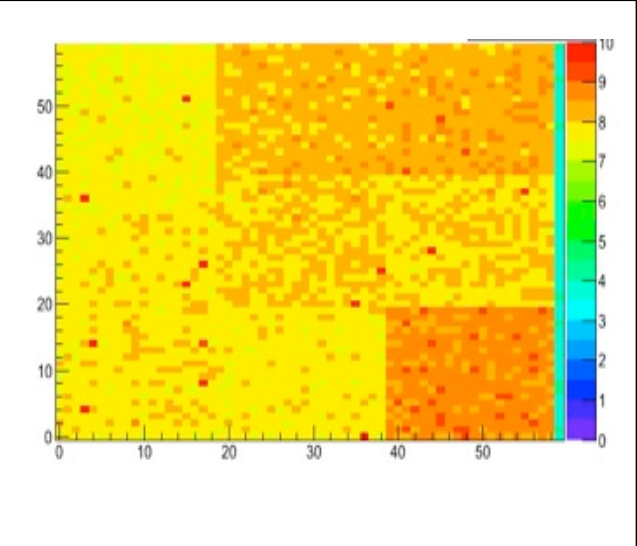
Analysis	M_p	
pixel size	$20 \times 20 \mu\text{m}^2$	$30 \times 30 \mu\text{m}^2$
Non-irradiated (not damaged)		
Irradiated (damaged)		

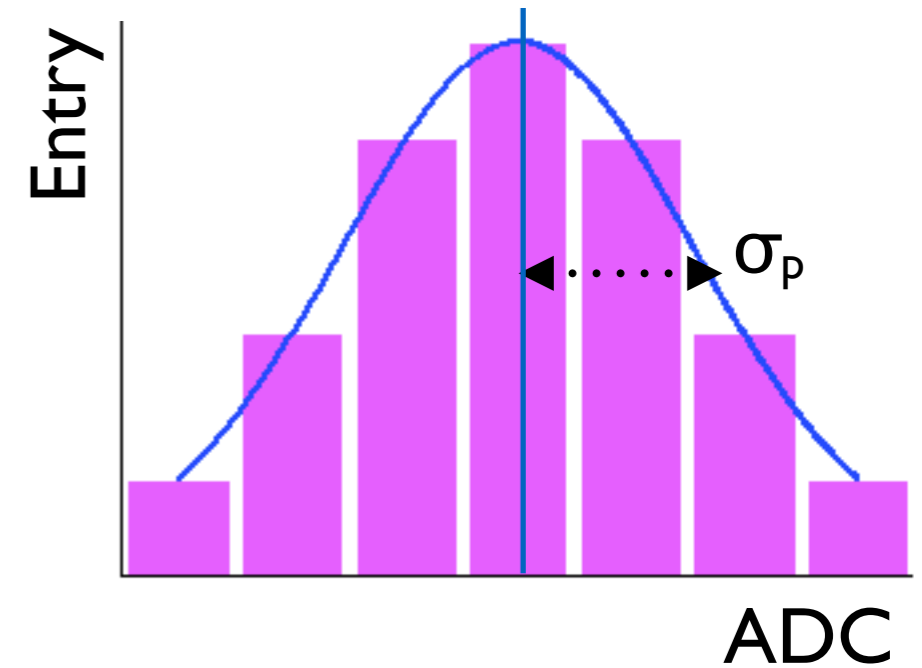


- Difference as the pixel sizes, anode types.
- No big difference of non-irradiated and irradiated pixel chip

Noise distribution

Measurement #10. in room temperature not stabilized

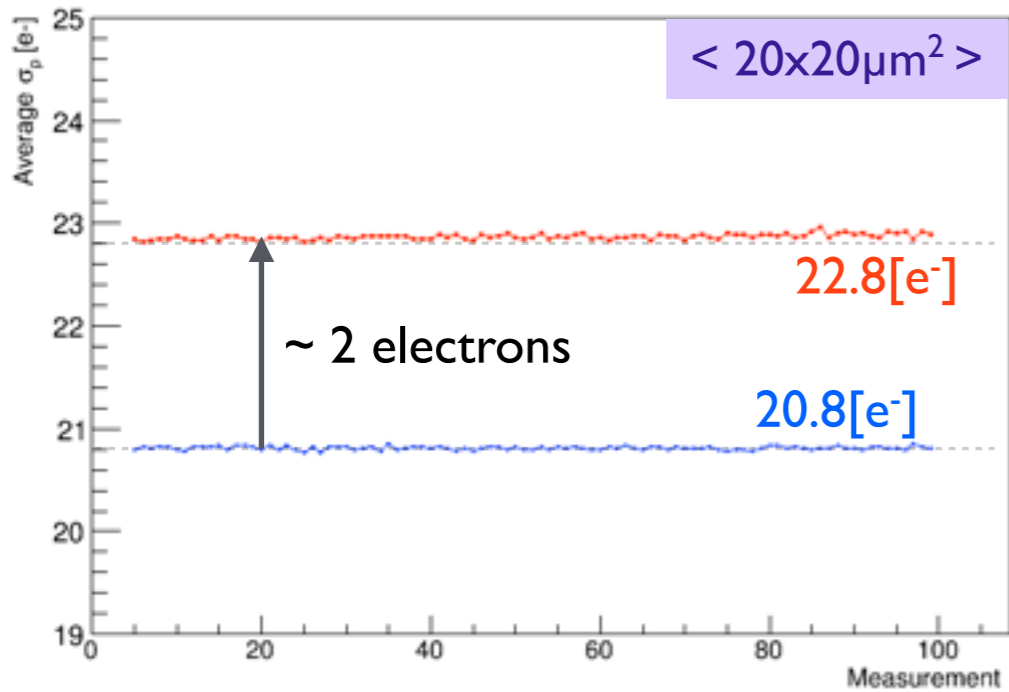
Analysis	σ_p	
pixel size	20x20 μm^2	30x30 μm^2
Non-irradiated (not damaged)		
Irradiated (damaged)		



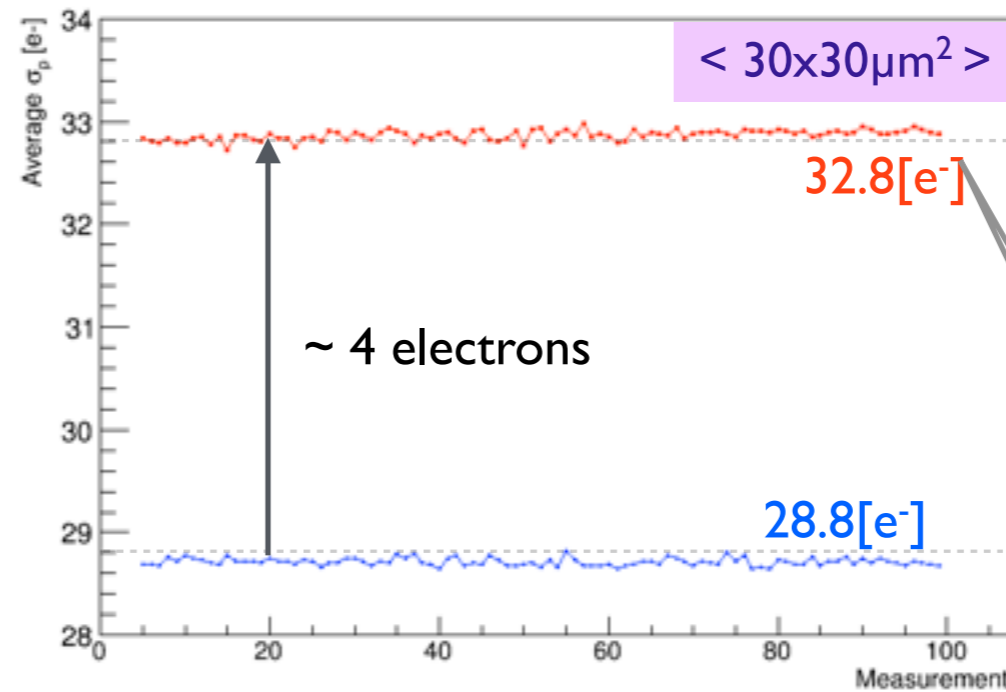
- In σ_p , Visible radiation effect

Average σ_p in Sector #6

Average σ_p vs. Measurement



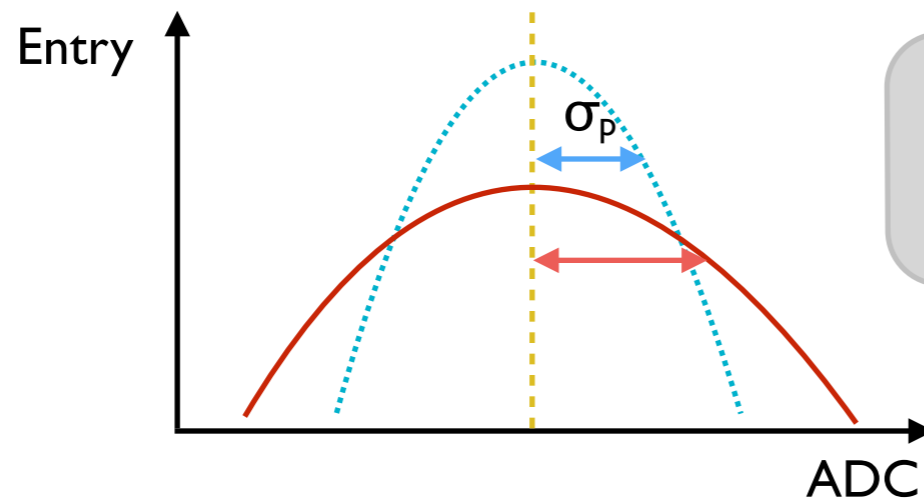
Average σ_p vs. Measurement



— non-irradiated
— irradiated

► Higher σ_p after Irradiation

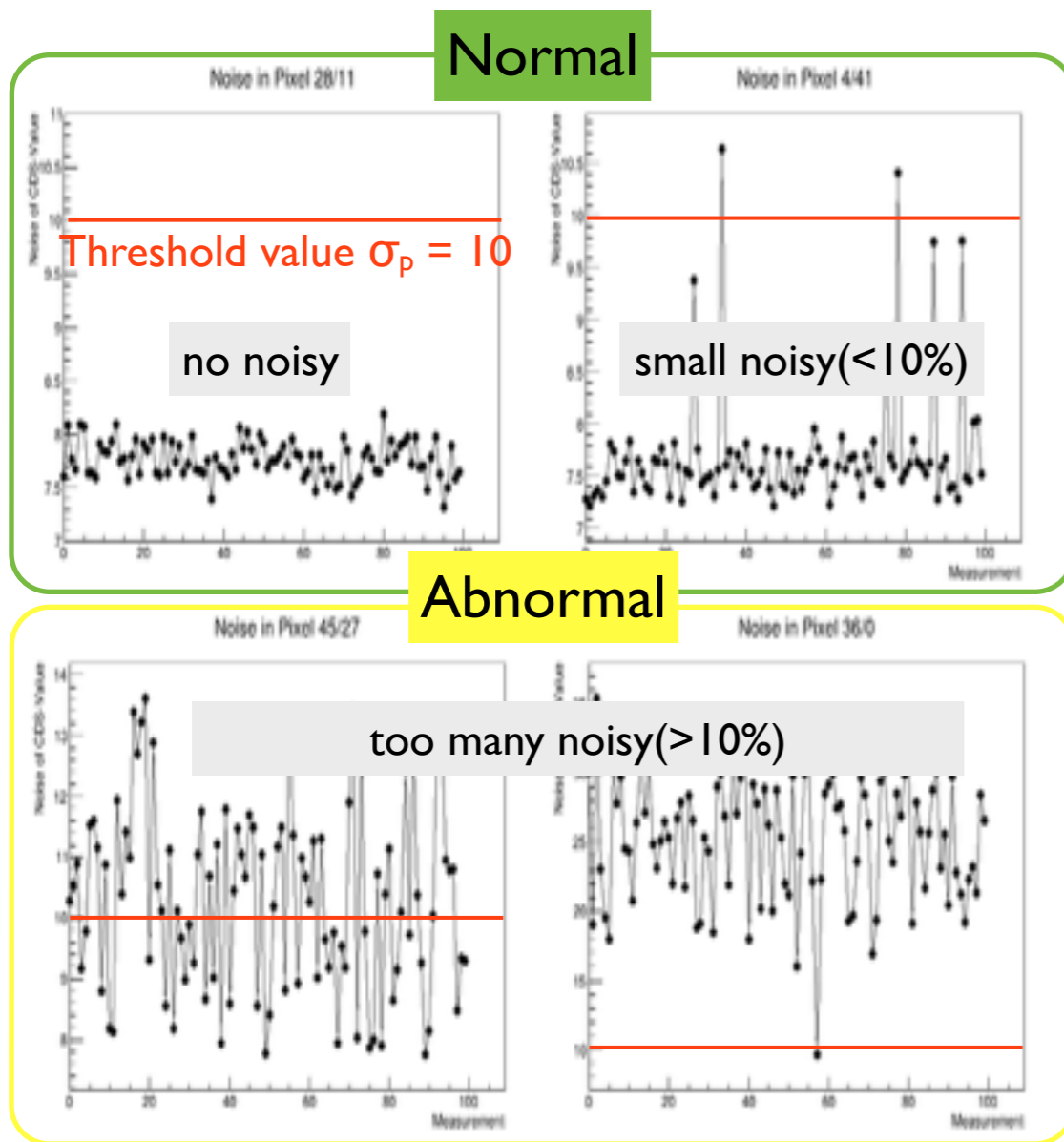
< Distribution of pedestal >



⇒ Broadened pedestal after irradiation

Noisy pixel Classification

* Noisy pixel: the Pixel with $\sigma_p > 10$ ADC, (about $40e^-$)



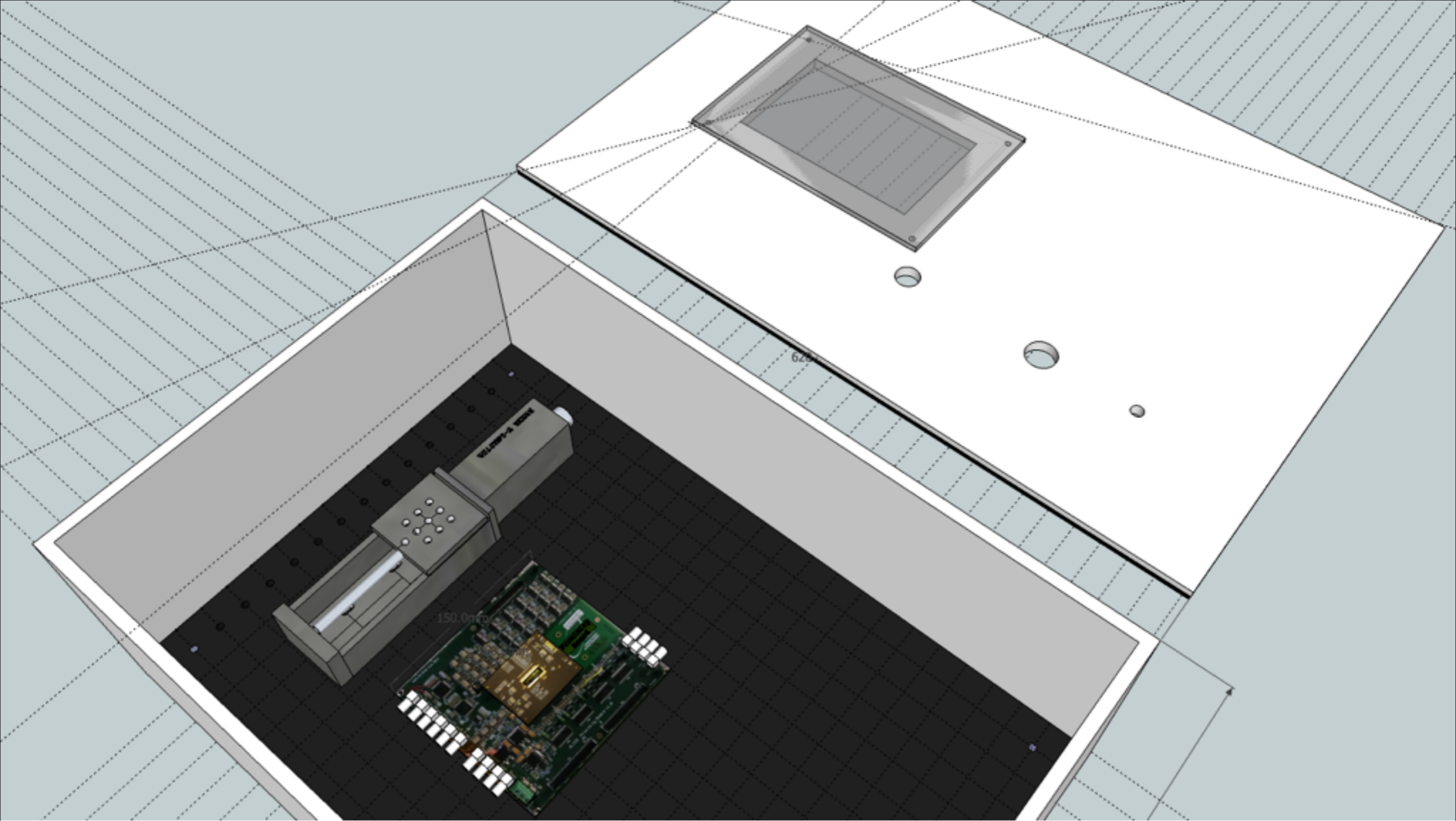
- Before irradiation
- After irradiation

Pixel size	20 x 20 μm^2		30 x 30 μm^2	
Kind	Normal	Abnormal	Normal	Abnormal
Before	99.96%	0.04%	100%	0%
After	99.91%	0.09%	99.69%	0.31%

⇒ Almost no effect after irradiation

Summary & Outlook

- Get started the R&D of the new ITS upgrade project: measurement of characteristics of the ITS prototype pixel chip.
- Broaden pedestal after radiation
- Abnormal pixel ratio is ignorable.
- Building up a characteristic measurement system for the pixel chips in PNU.



Thank you